

N-Ch MOSFET

General Description

The WSP05N15 is the highest performance trench N-Ch MOSFET with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The WSF05N10 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

Product Summery

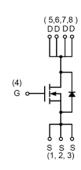
BVDSS	RDSON	ID
150V	37mΩ	6A

Applications

- Power Management for Boost Converters.
- Synchronous Rectifiers for SMPS.
- LED Backlighting.

SOP-8 Pin Configuration





Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	150	V
V_{GS}	Gate-Source Voltage	±25	V
I _D @T _c =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	6.0	А
I _D @T _c =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	4.8	А
I _{DM}	Pulsed Drain Current ²	24	А
EAS	Single Pulse Avalanche Energy ³	36	mJ
I _{AS}	Avalanche Current	12	А
P _D @T _A =25℃	Total Power Dissipation⁴	3.5	W
T _{STG}	Storage Temperature Range -55 to 150		$^{\circ}\!\mathbb{C}$
TJ	Operating Junction Temperature Range -55 to 150		$^{\circ}$

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R _{0JA}	Thermal Resistance Junction-ambient ¹		70	°C/W
R _{eJC}	Thermal Resistance Junction-Case ¹		24	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0V , I_D =250uA	150			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.098		V/°C
В	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =6A		37	45	mΩ
R _{DS(ON)}		V _{GS} =6V , I _D =2A		48	78	
$V_{GS(th)}$	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	2.0	3.0	4.0	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} -V _{DS} , I _D -250uA		-5.52		mV/℃
	Drain Source Leakage Current	V_{DS} =80V , V_{GS} =0V , T_J =25 $^{\circ}$ C			10	· uA
I _{DSS}	Drain-Source Leakage Current	V_{DS} =80V , V_{GS} =0V , T_{J} =55 $^{\circ}$ C			100	uA
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm 20 V$, V_{DS} = $0 V$			±100	nA
gfs	Forward Transconductance	V_{DS} =5V , I_D =3A		6.2		S
R_g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.5	3.2	Ω
Qg	Total Gate Charge (10V)			23	33	
Q_gs	Gate-Source Charge	V _{DS} =50V , V _{GS} =10V , I _D =3A		6		nC
Q_{gd}	Gate-Drain Charge			9.9		
T _{d(on)}	Turn-On Delay Time			5.5	21.6	
Tr	Rise Time	V_{DD} =30V , V_{GS} =10V , R_{G} =6 Ω		27	48.6	
$T_{d(off)}$	Turn-Off Delay Time	$I_D=1A$,RL=30 Ω .		56	112	ns
T _f	Fall Time			24	48	
Ciss	Input Capacitance			1160	1500	
C _{oss}	Output Capacitance	V _{DS} =30V , V _{GS} =0V , f=1MHz		90		pF
C _{rss}	Reverse Transfer Capacitance			45		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.5mH , I _{AS} =12A	30			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I _S	Continuous Source Current ^{1,6}	V _G =V _D =0V , Force Current			4.0	Α
I _{SM}	Pulsed Source Current ^{2,6}				24	Α
V_{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =4A , T _J =25℃			1.3	V
t _{rr}	Reverse Recovery Time	-IF=6A, dI/dt=100A/μs,T _J =25℃		31		nS
Q _{rr}	Reverse Recovery Charge			50		nC

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t<10 sec.
- 2.The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.5mH, I_{AS} =12A
- 4.The power dissipation is limited by 150 °C junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

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Typical Characteristics

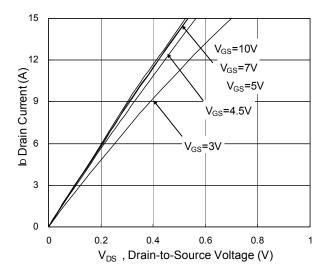


Fig.1 Typical Output Characteristics

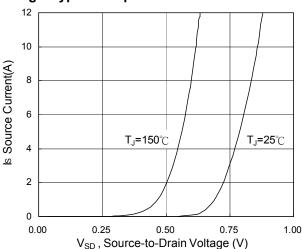


Fig.3 Forward Characteristics Of Reverse

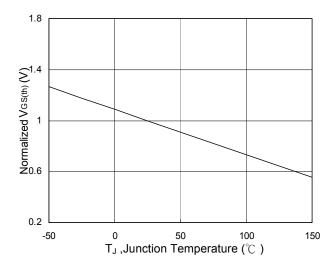


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

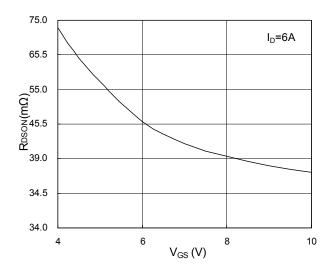


Fig.2 On-Resistance vs. Gate-Source

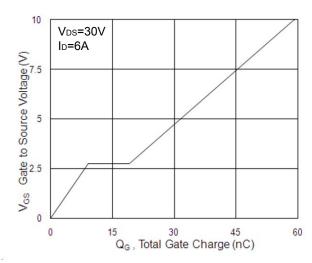


Fig.4 Gate-Charge Characteristics

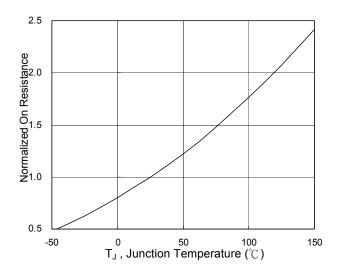
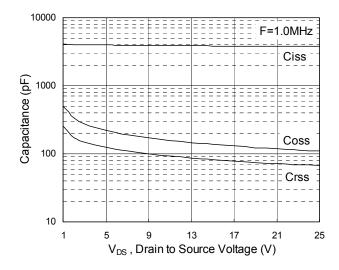


Fig.6 Normalized R_{DSON} vs. T_{J}





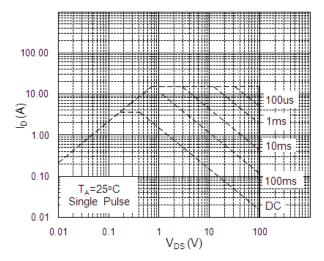


Fig.7 Capacitance

Fig.8 Safe Operating Area

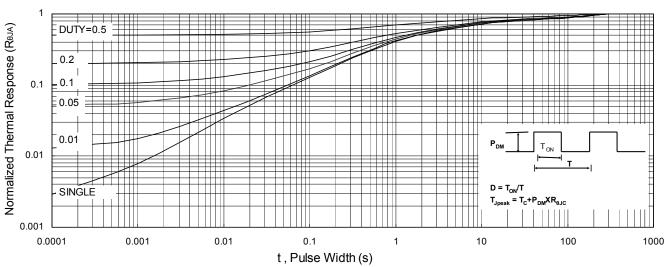


Fig.9 Normalized Maximum Transient Thermal Impedance

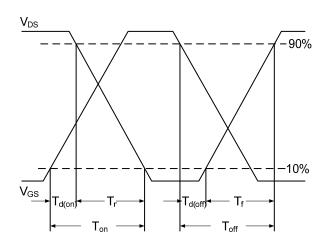


Fig.10 Switching Time Waveform

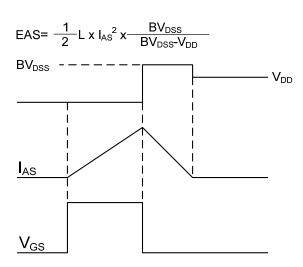


Fig.11 Unclamped Inductive Switching Waveform



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